

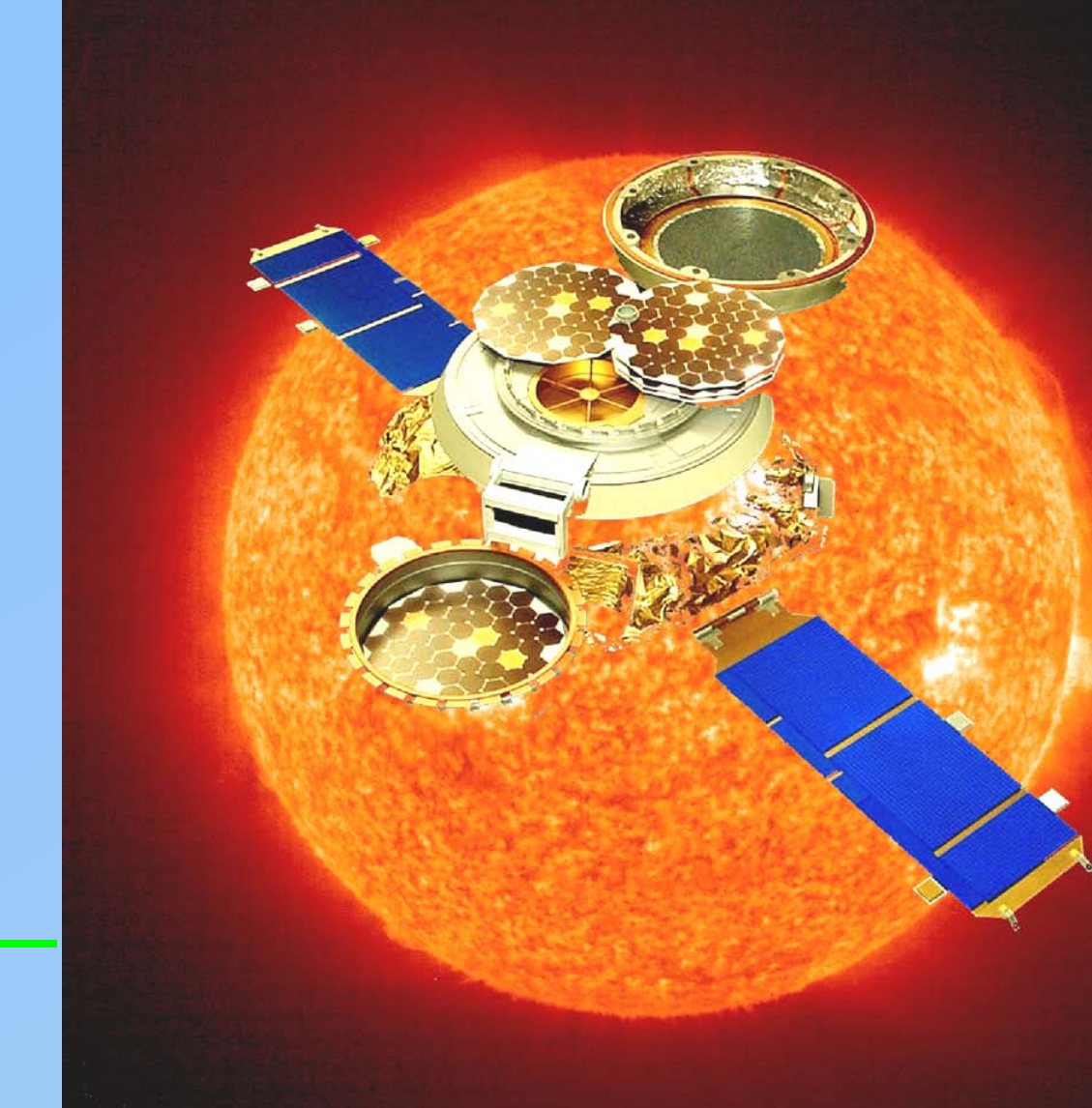


Dr. Don Burnett
CalTech
Genesis Lead PI

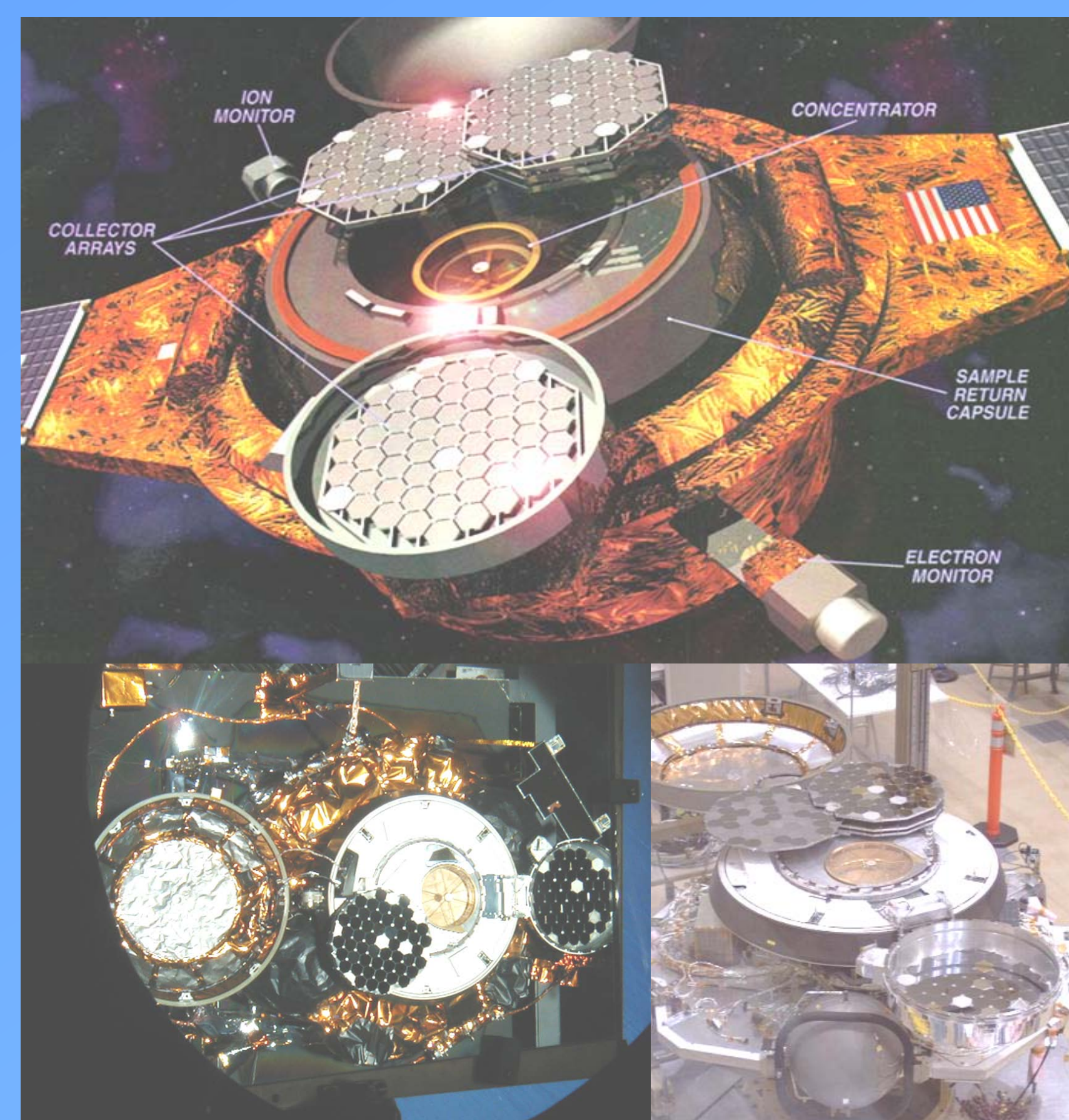
Welcome to Genesis Solar Wind Curation Laboratory

Preparation to Launch

Genesis
Capturing
the Sun



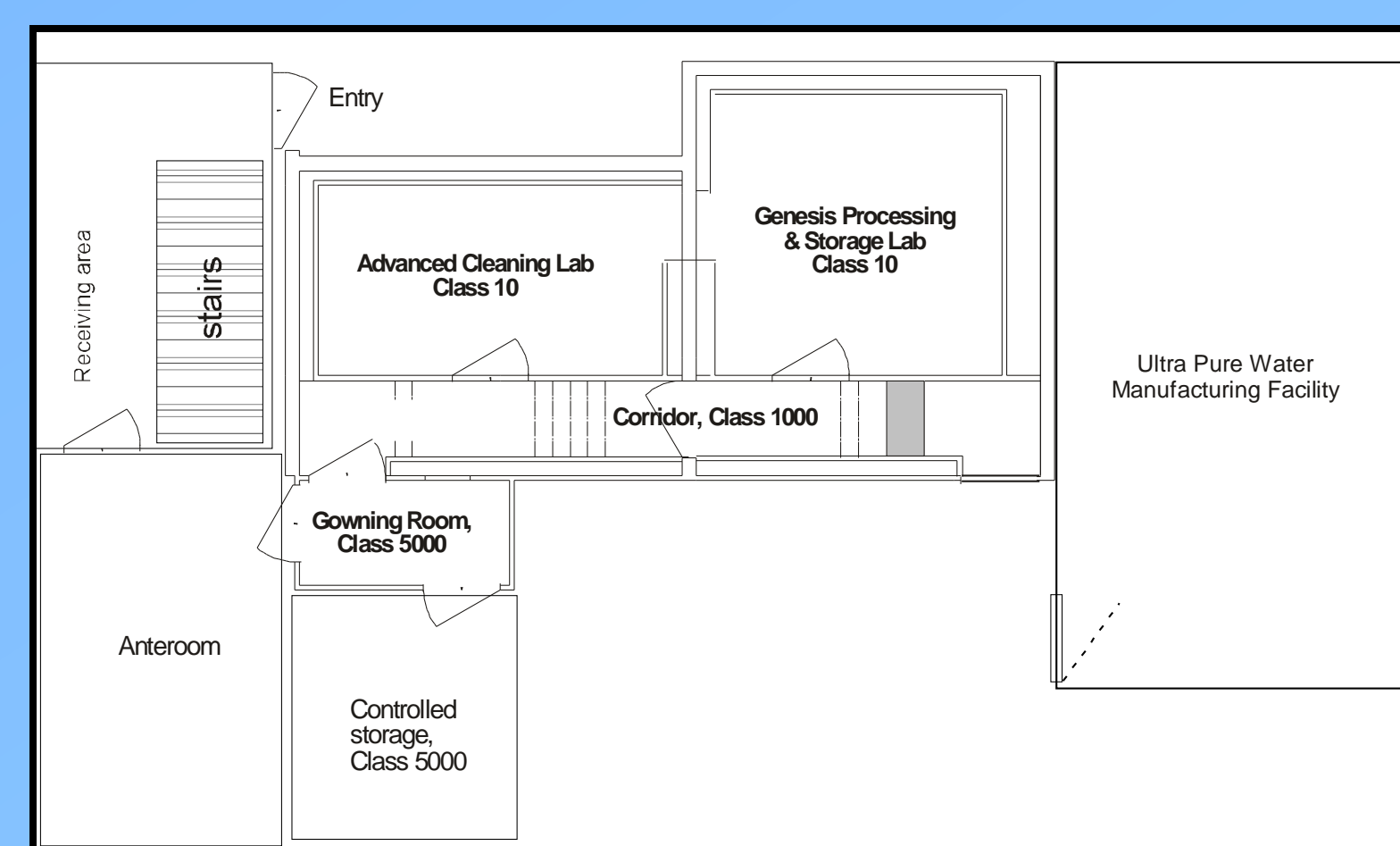
Genesis Regime Collector Design



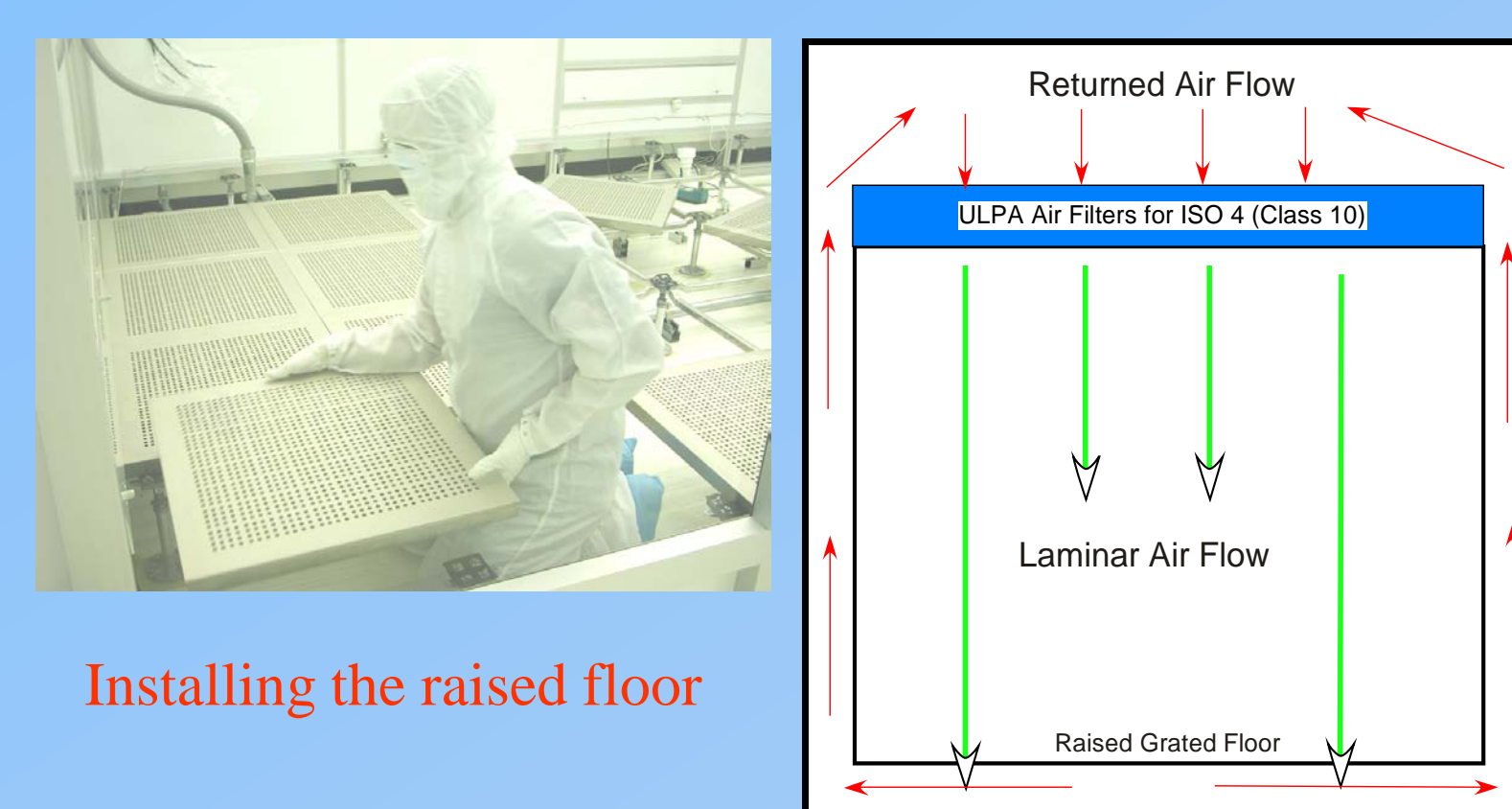
JSC Wafer Testing



ISO 4 (Class 10) Cleanroom Design



ISO 4 (Class 10) Airflow Design



Installing the raised floor



Assembly of the Science Payload Canister



Ultrapure Water and Ultrasonic Cleaning and Inspection of the array collector grids.



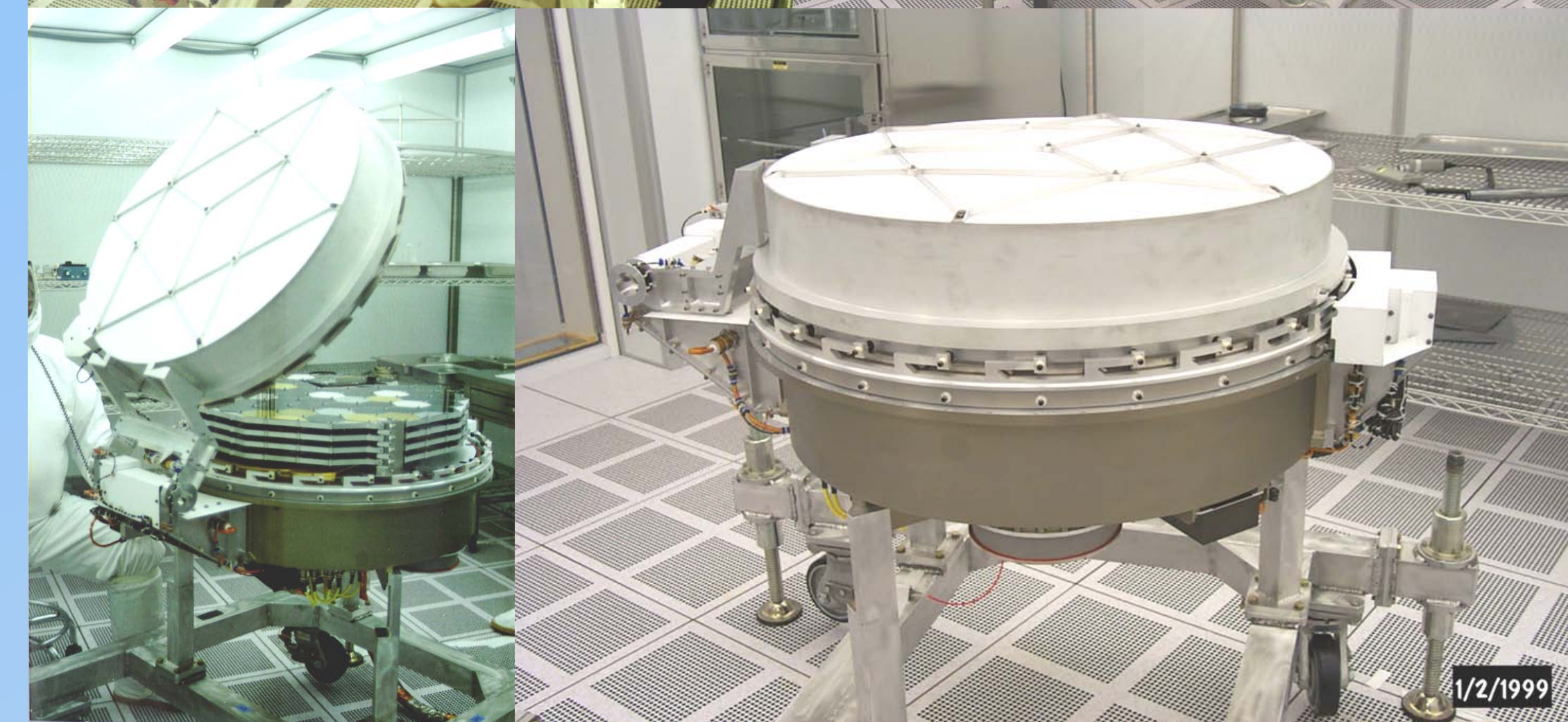
Installation of nine ultrapure hexagonal array materials for solar wind regime capture.

Completion of Array Material Installation



Final preparations and closure of the science canister payload.

Next Step, Lagrange 1 Solar Wind Exposure.



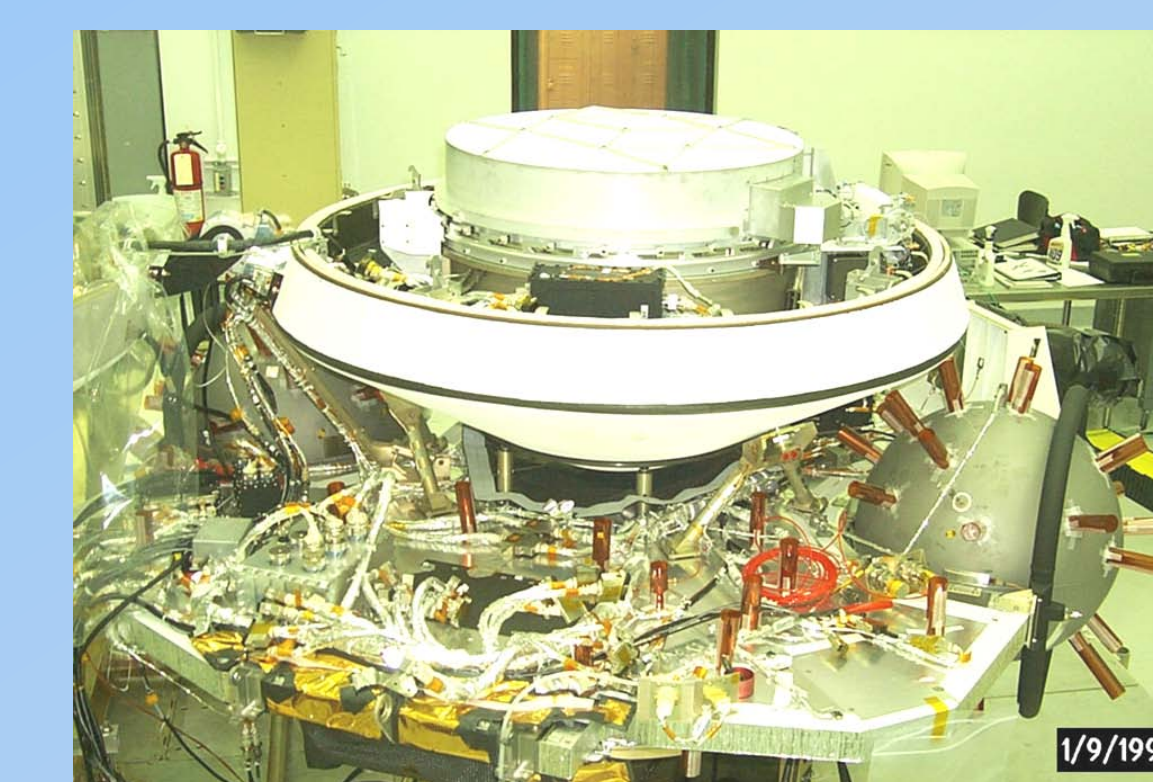
Shipment of Science Canister Payload from JSC for integration with spacecraft at Lockheed Denver facility.



Lockheed Martin Denver Facility Assembly of the Genesis Spacecraft



Science Canister Payload Integration



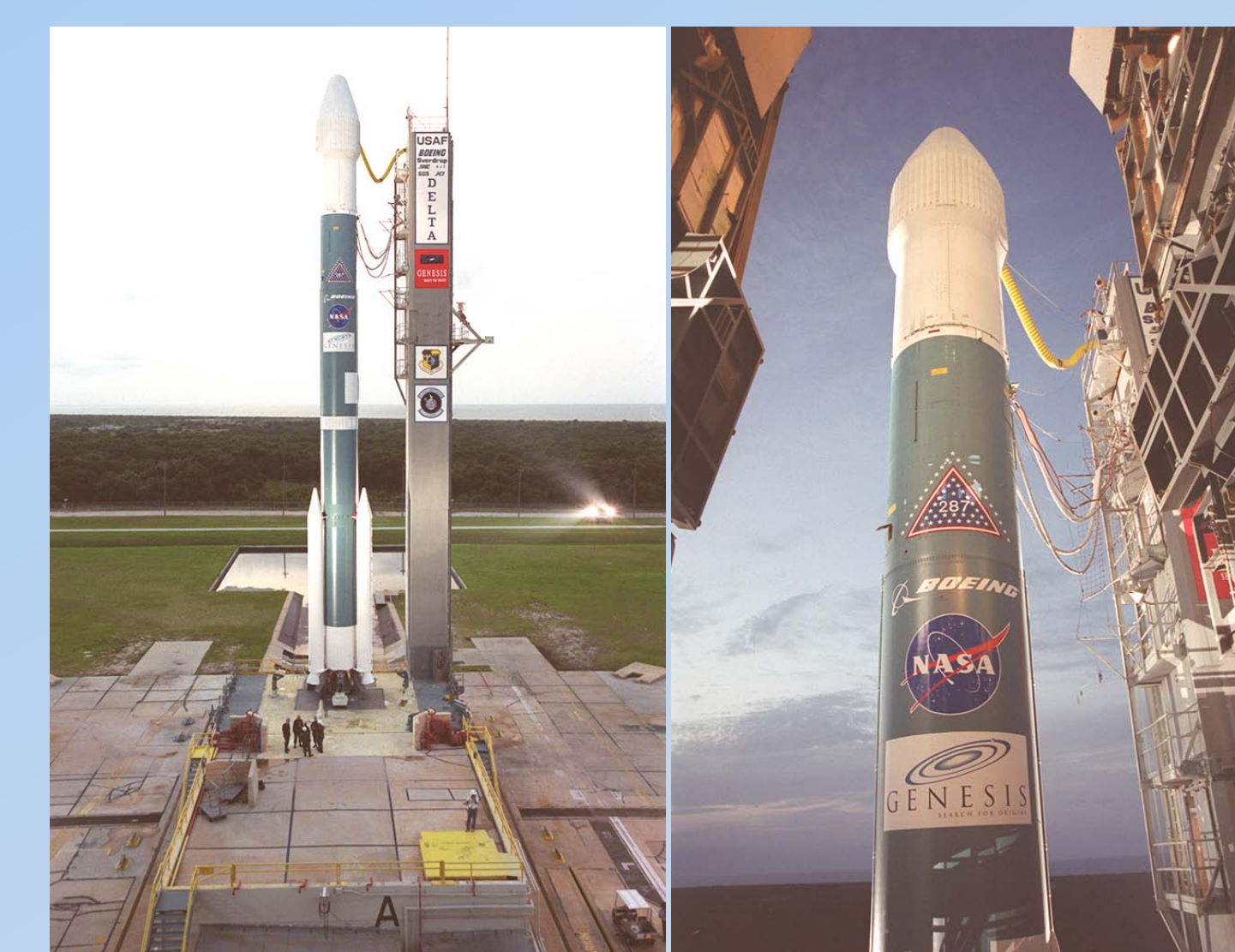
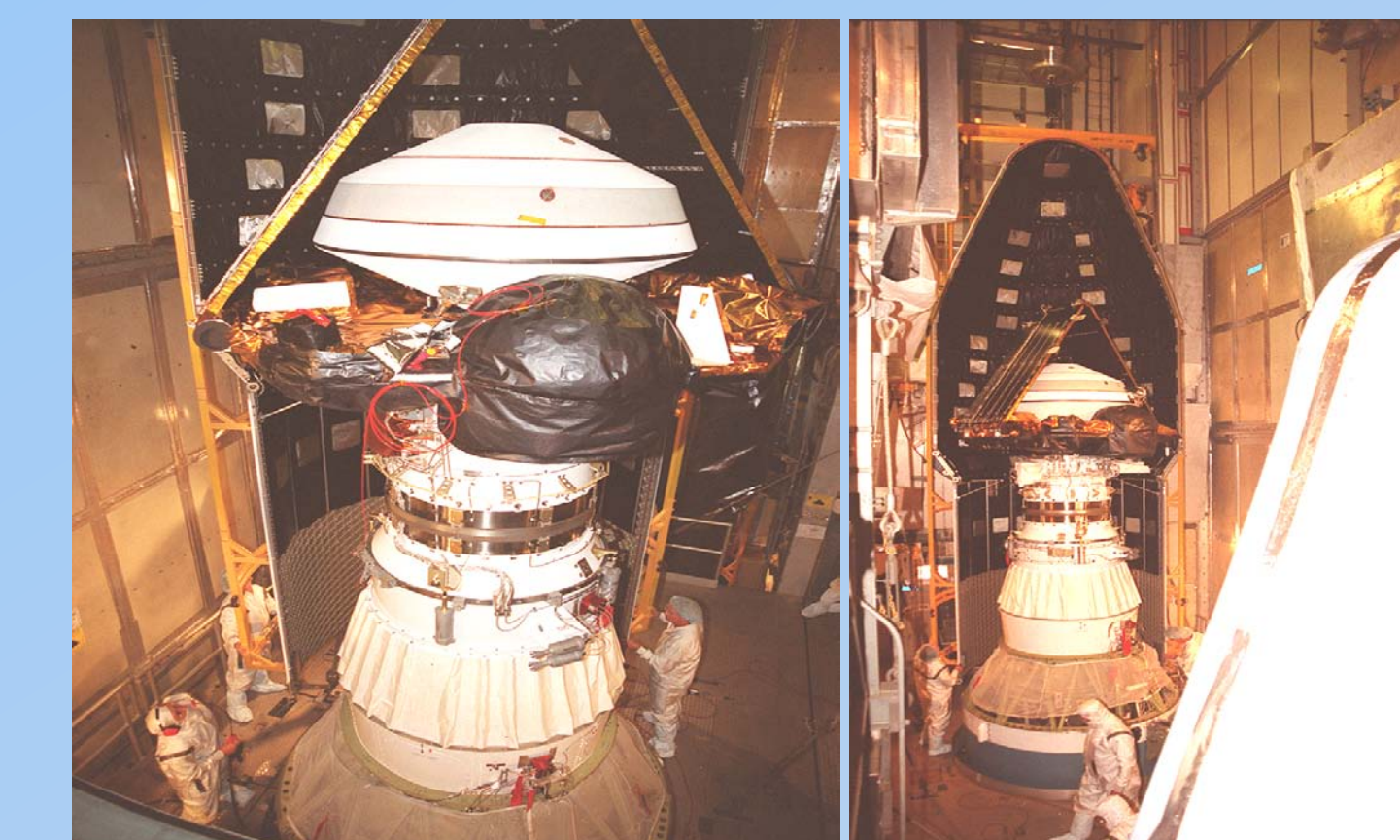
Final Preparations and Testing



Genesis Spacecraft Shipping to Kennedy Space Center



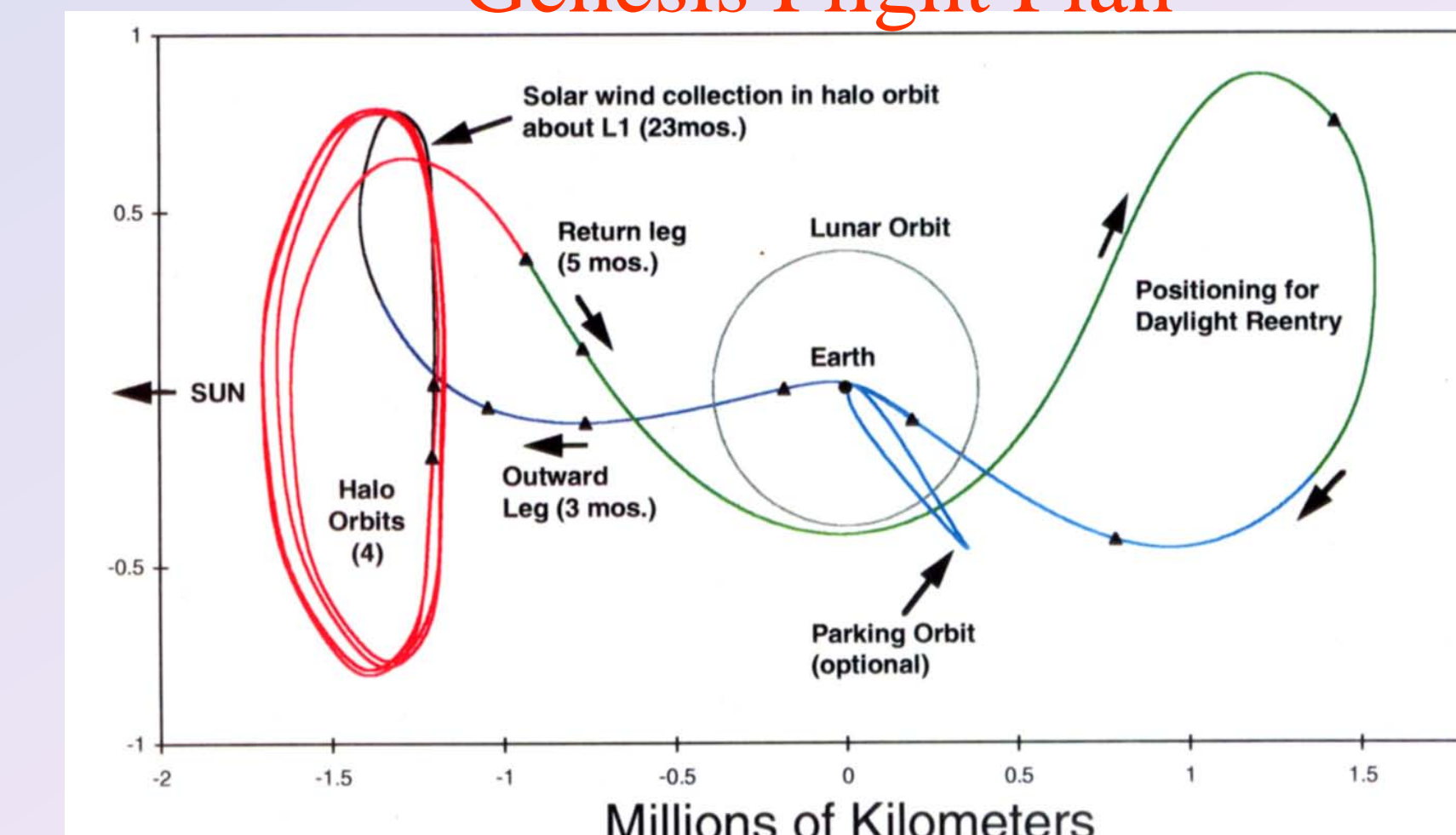
Launch Preparations at KSC

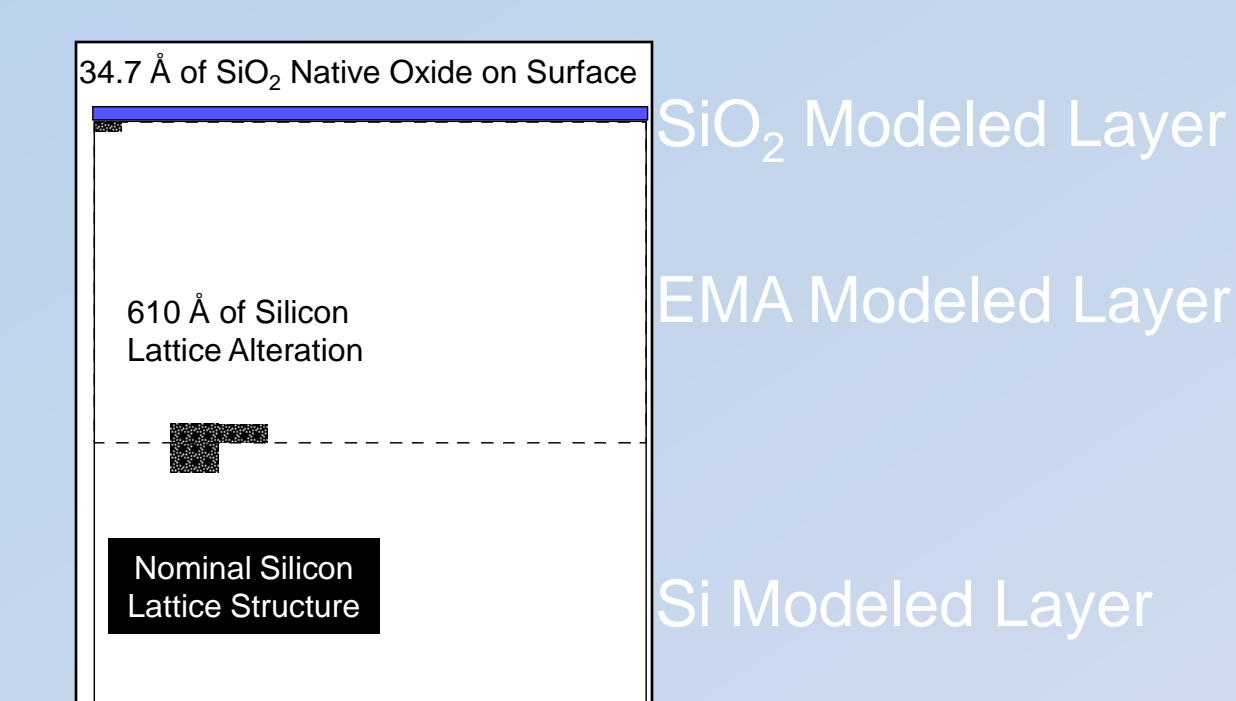
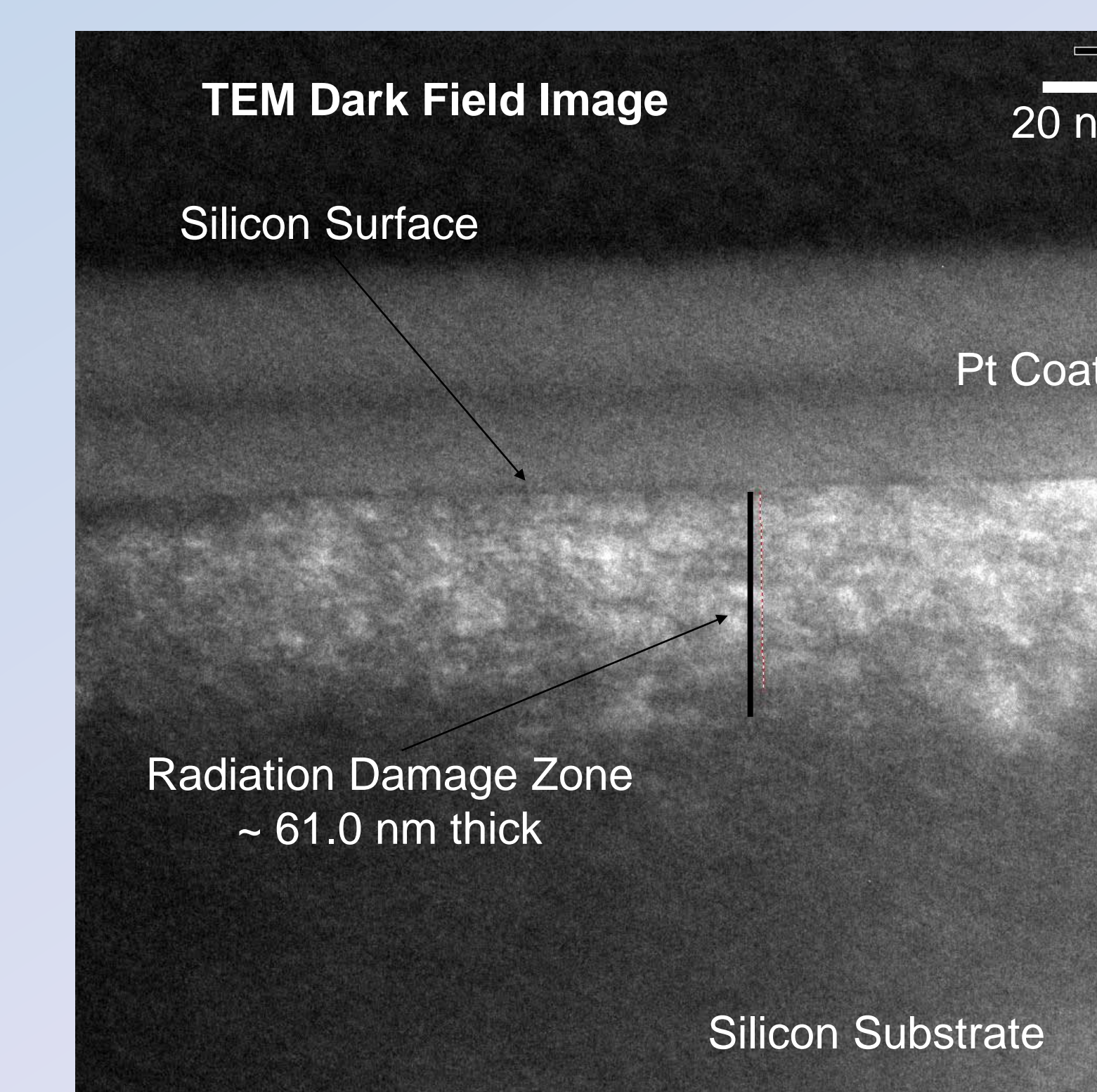
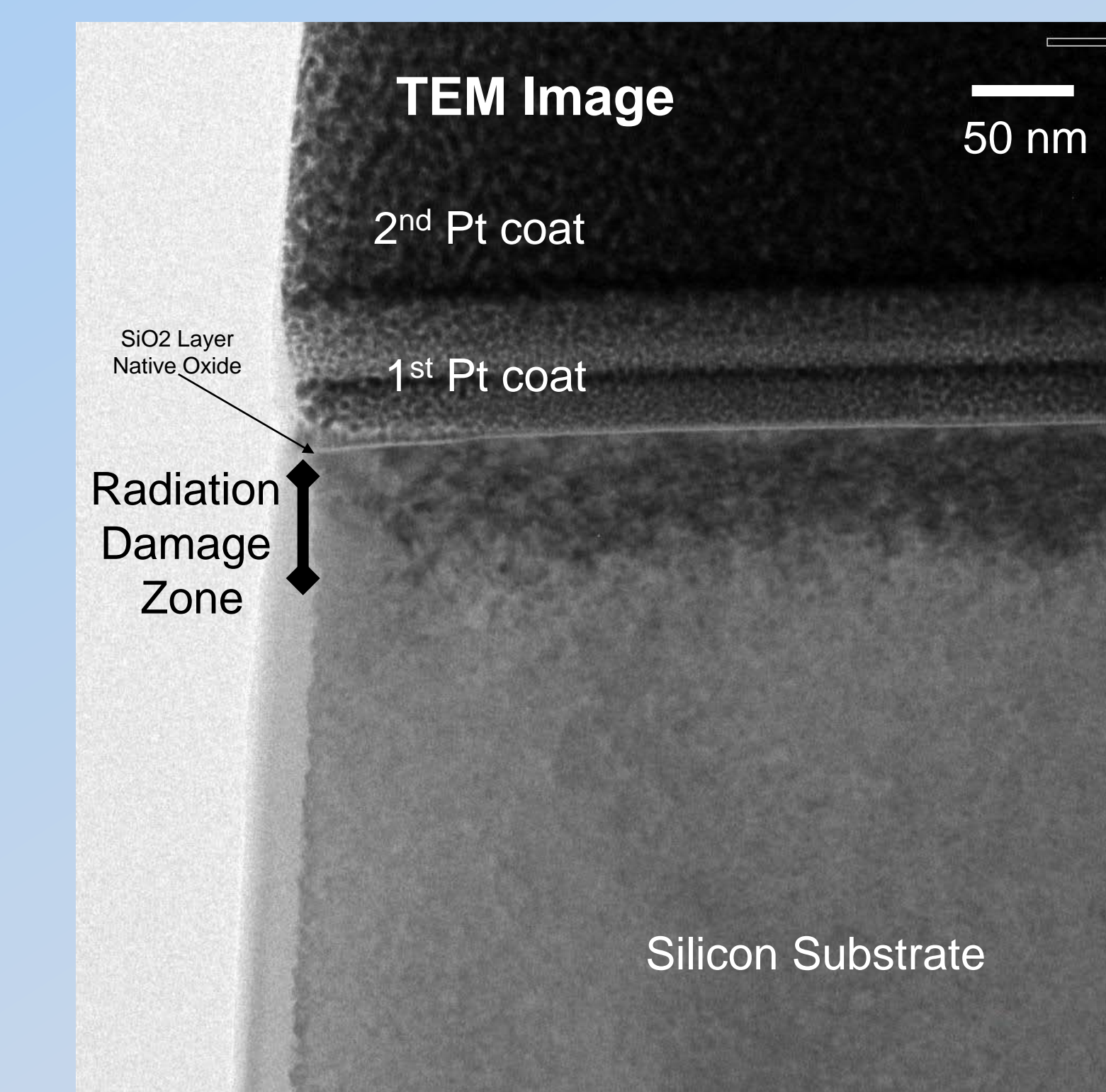
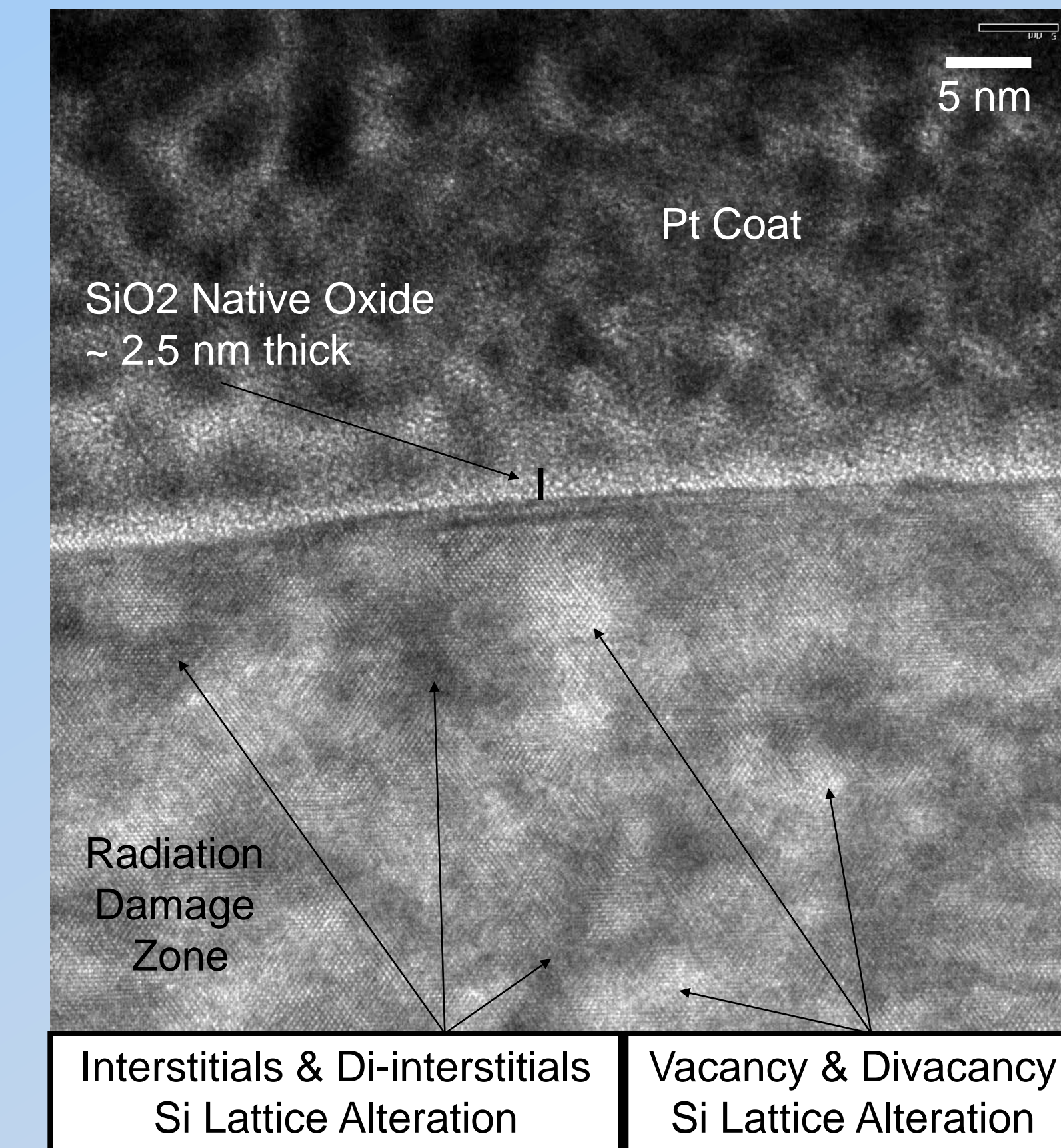
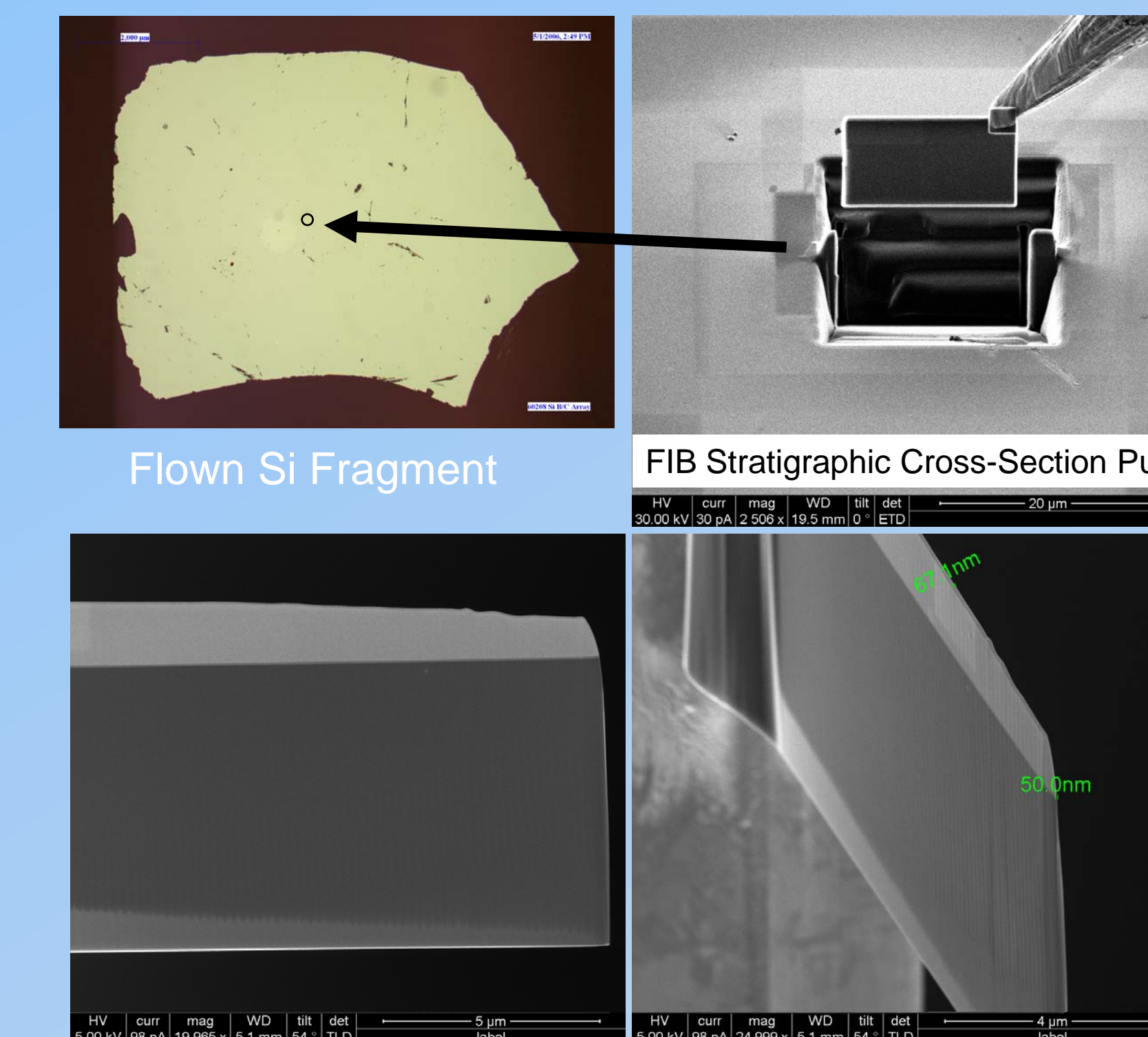


Launch of Discovery Mission Genesis



Genesis Flight Plan





TEM Results and Future Work

The B/C array silicon substrate lattice structure shows signs of multiple vacancies and interstitial nodes in approximately the first 600 Å below the native oxide layer. This is primarily due to the accumulation of bombarding hydrogen and helium ions from the solar wind. The radiation damaged zone can be interpreted roughly as the bulk solar wind implantation zone. Therefore, the Genesis Mission was successful in capturing atoms from the sun as seen by the TEM images.

The thickness measurement of the damaged region can also provide a gross check for the concentration of hydrogen atoms collected by the Genesis mission. This radiation damage zone can also provide an insight into the fluence threshold required to alter Si materials, which is below 2×10^{16} atoms/cm² for solar wind exposure.

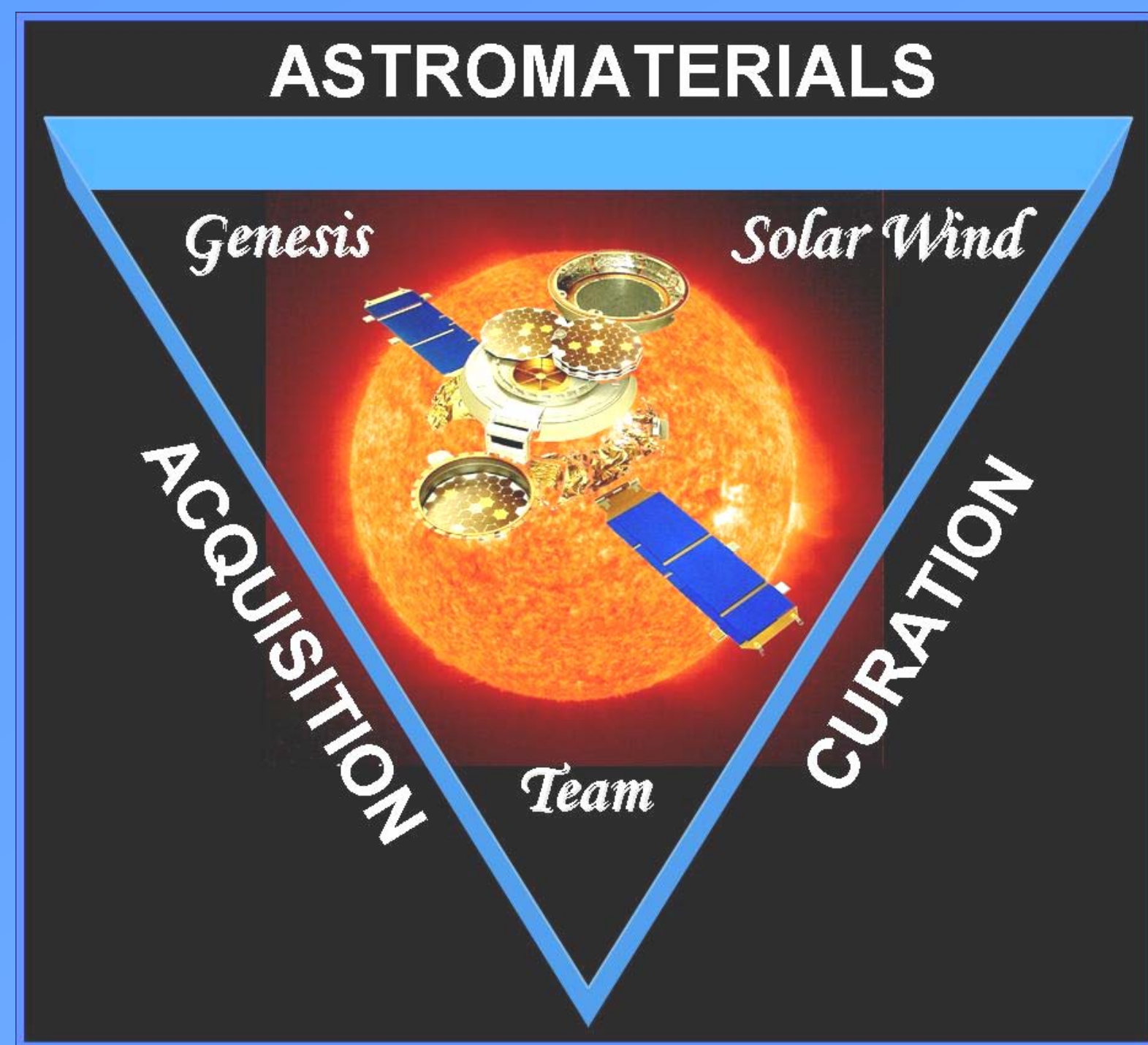
The spacecraft was in continual Halo orbit at L1 while the bulk collector arrays were deployed and is the first look at solar wind radiation damage outside the magnetosphere at L1. This study provides a direct measurement of how solar wind effects silicon over time. Since silicon is a well studied semiconductor material, a future model of the damage threshold could be used for assessing lifespan of future spacecraft and solar panel materials in space outside the magnetosphere when exposed to solar wind.

Acknowledgements

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ARES at NASA Johnson Space Center

FIB Pull Team: Nick Teslich, John Bradley & Giles Graham
Lawrence Livermore National Laboratory

Genesis Curation Team: Judy Allton & Melissa Rodriguez
ARES at NASA Johnson Space Center



Genesis Curation Team

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Solar Wind Curator (NASA)

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Laboratory Lead (ESCG)

Melissa Rodriguez
Sample Processor (ESCG)

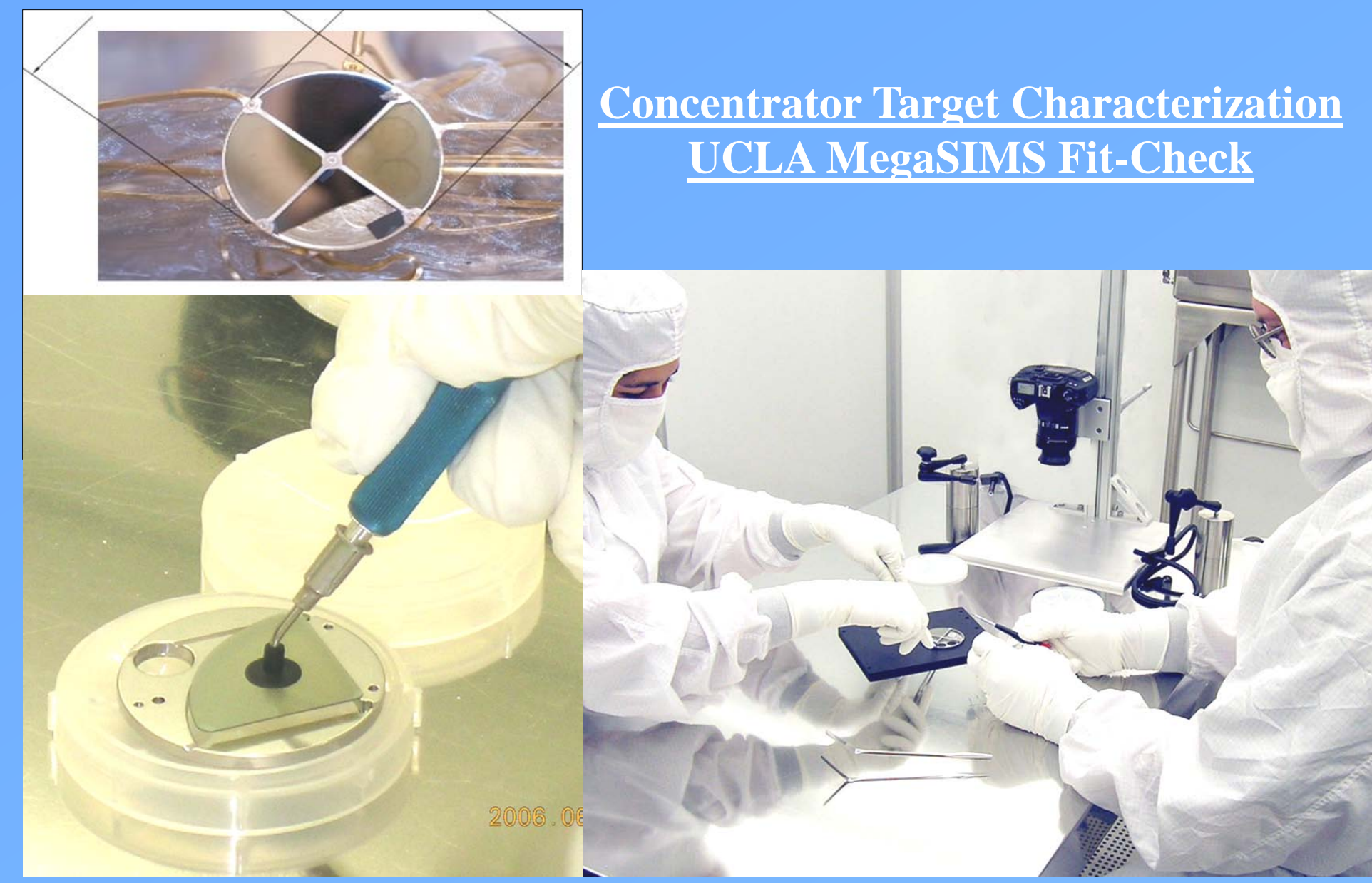


Genesis Curation Laboratory's Mission

- Protect and curate the United States limited resource of solar wind samples for future studies.
- Allocate solar wind samples to the multinational science community for study as directed by NASA and CAPTEM.
- Characterize all flown samples and develop a solar wind sample catalog.
- Maintain an auditable inventory.
- Conduct wafer alteration and contamination assessments.
- Remove particular and molecular contamination.

Solar Wind Sample Characterization

- Assess Material Type > 15,000 samples from 5 array frames once held 9 different types of ultra-pure semiconductor wafers. Other Genesis Materials: Concentrator Targets, bulk metallic glass, gold foil, polished aluminum, & Mo-Pt.
- Measure size and area of sample
- Assess the four types of Solar Wind Regime via wafer thickness: Bulk (B/C), coronal mass ejection (E), high speed (H), & Low speed (L) solar wind).
- Assess Particle Contamination > 0.3 micron size particles using optical microscopy
- Assess Molecular Contamination > 1 angstrom thick films using spectroscopic ellipsometry
- Assess silicon types (float-zone or Czochralski) via FT-IR Spectroscopy



Genesis Sample Cabinets

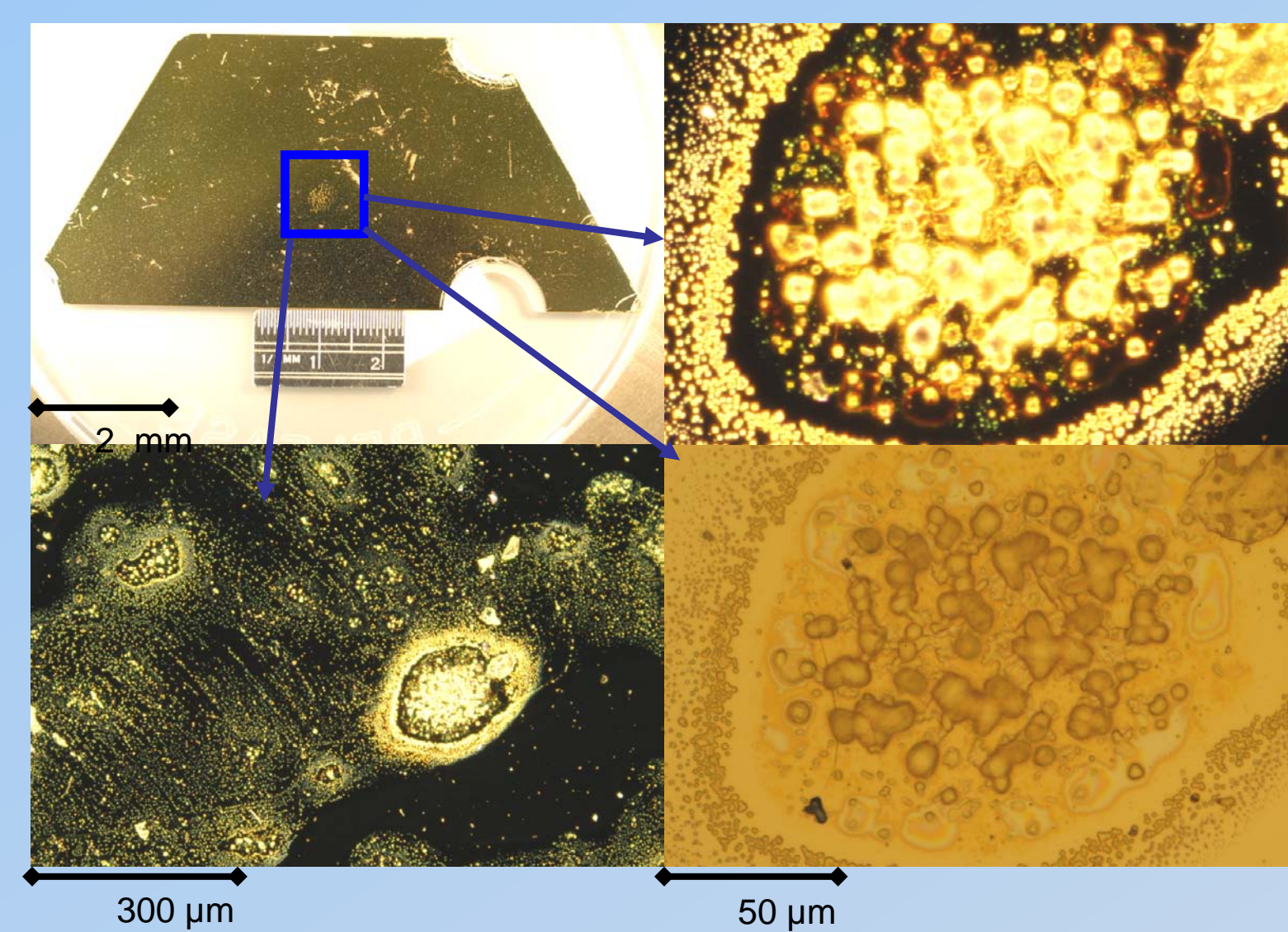
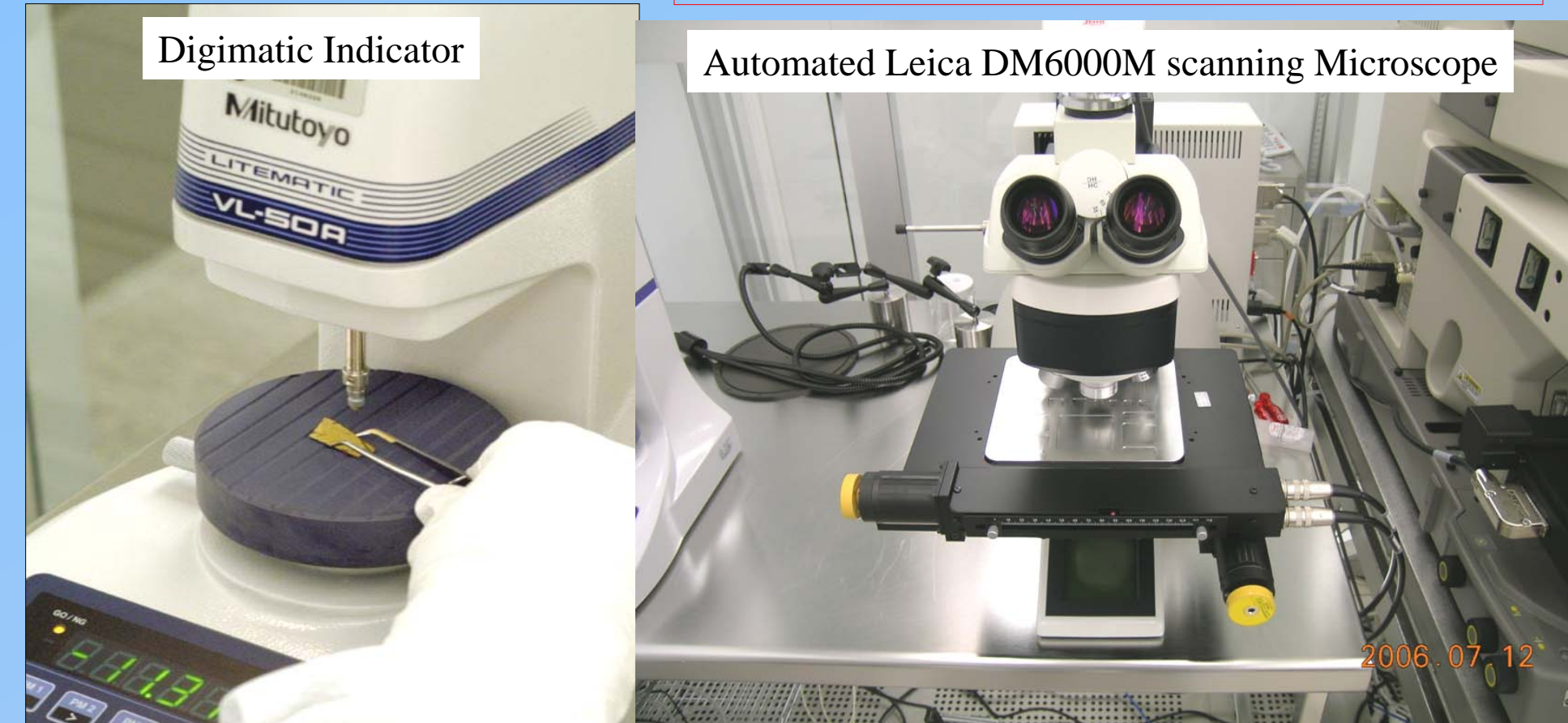


Genesis Sample Cabinet in Lunar RSV



Wafer Thickness: Preliminary Solar Wind Regime Identification

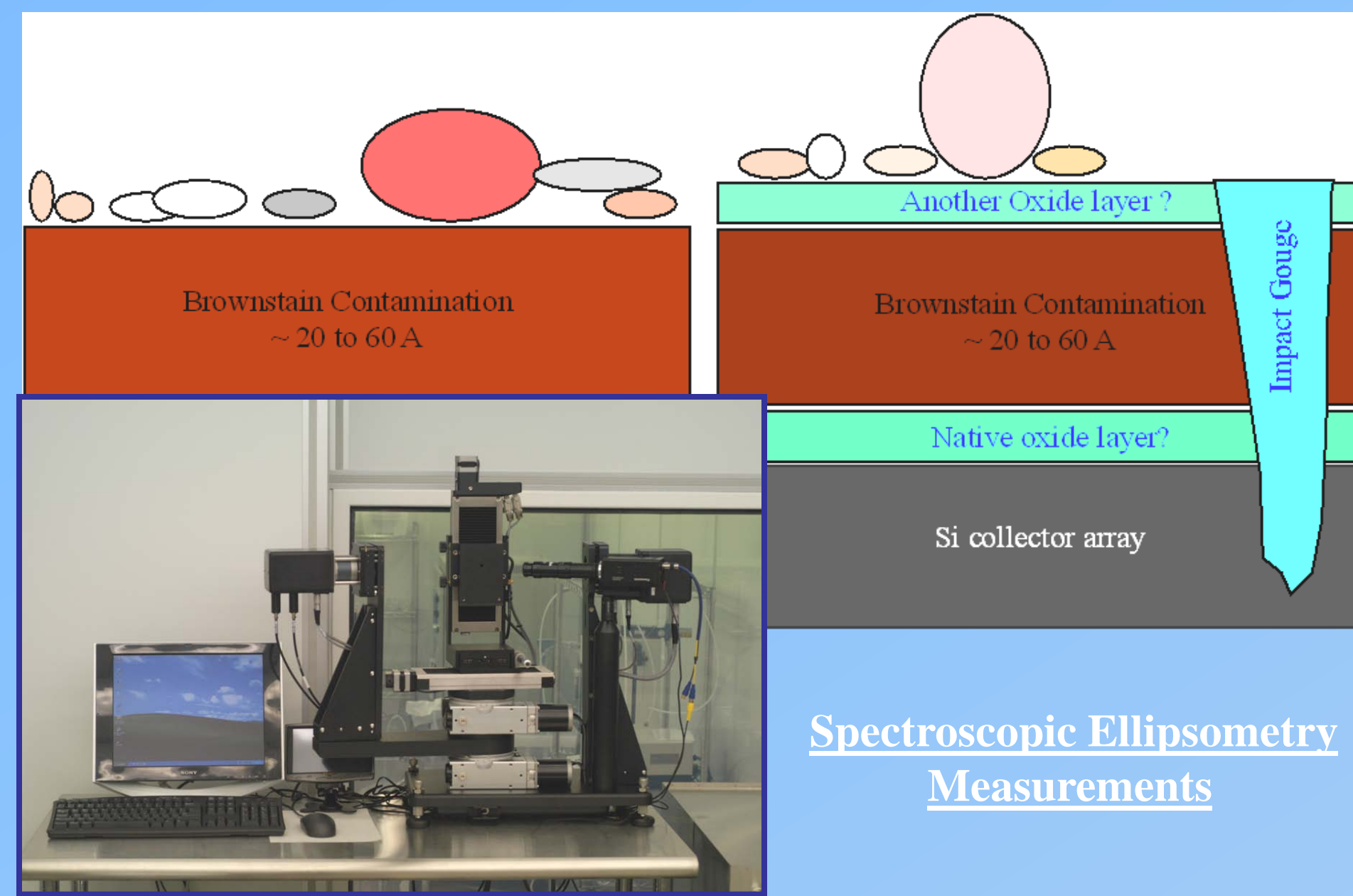
B & C Array (Bulk Solar Wind) = 700 μ m
E Array (Coronal Mass Ejections) = 650 μ m
H Array (High Speed Solar Wind) = 600 μ m
L Array (Low Speed Solar Wind) = 550 μ m



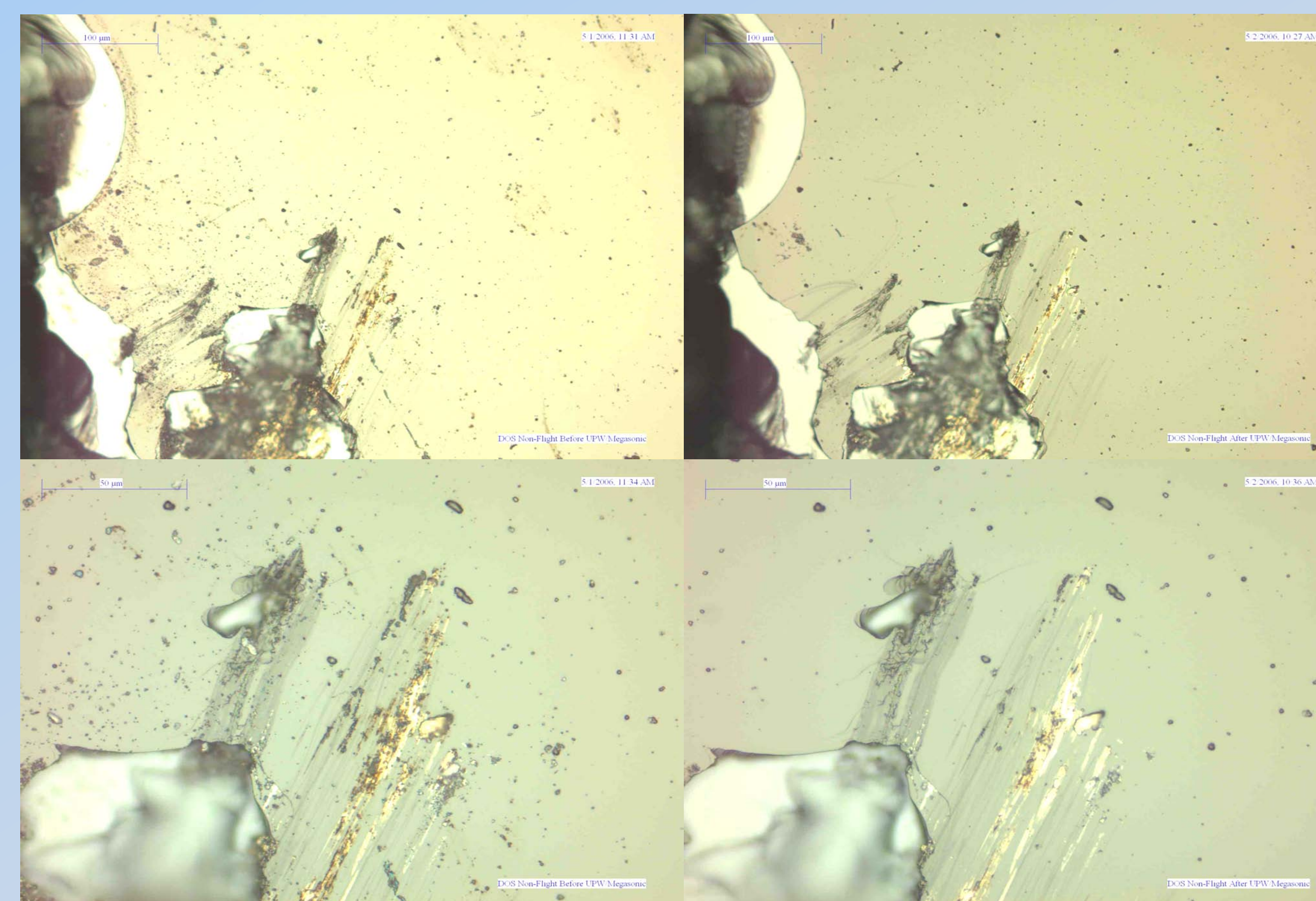
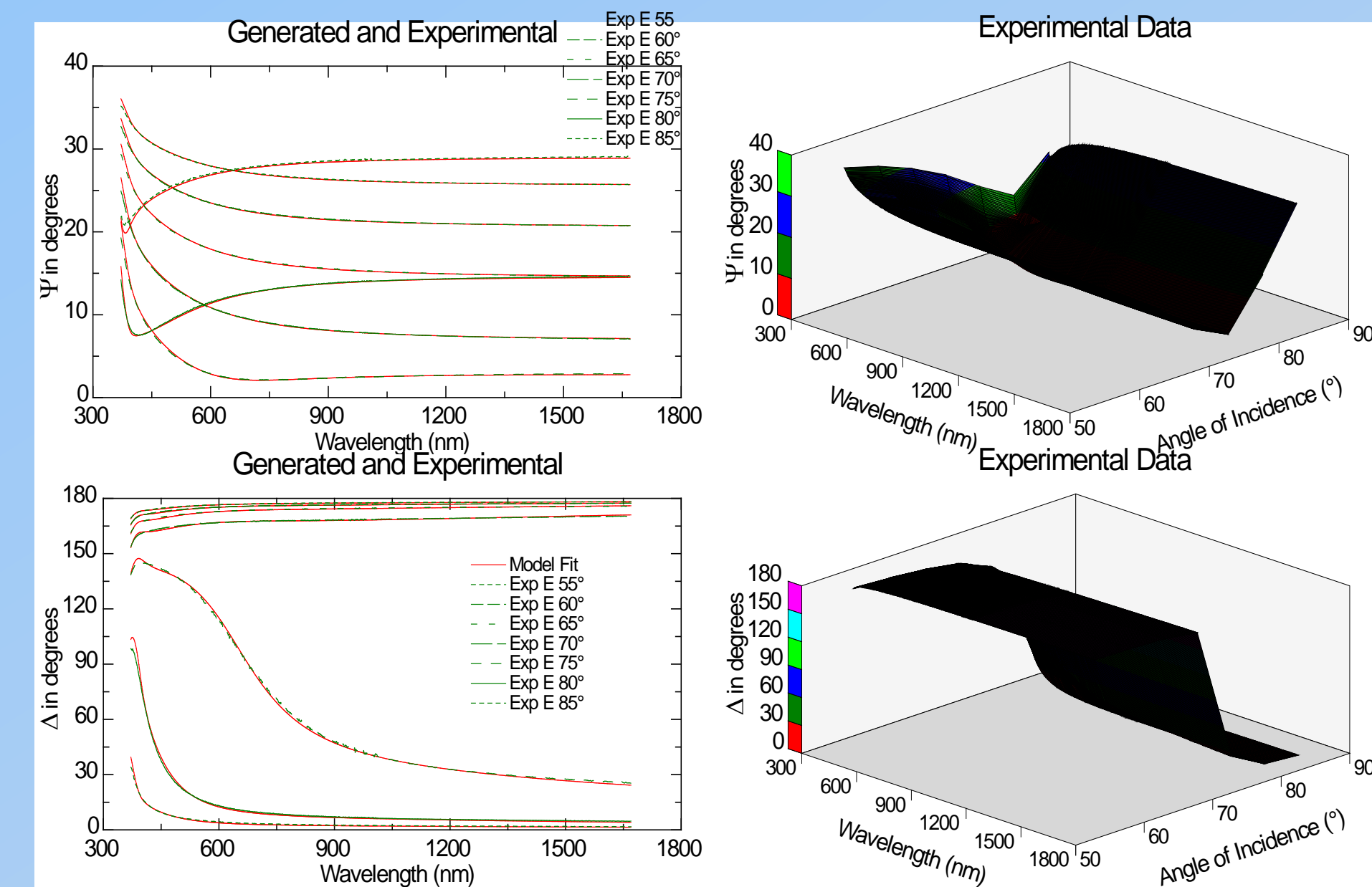
Ellipsometer



Microscope



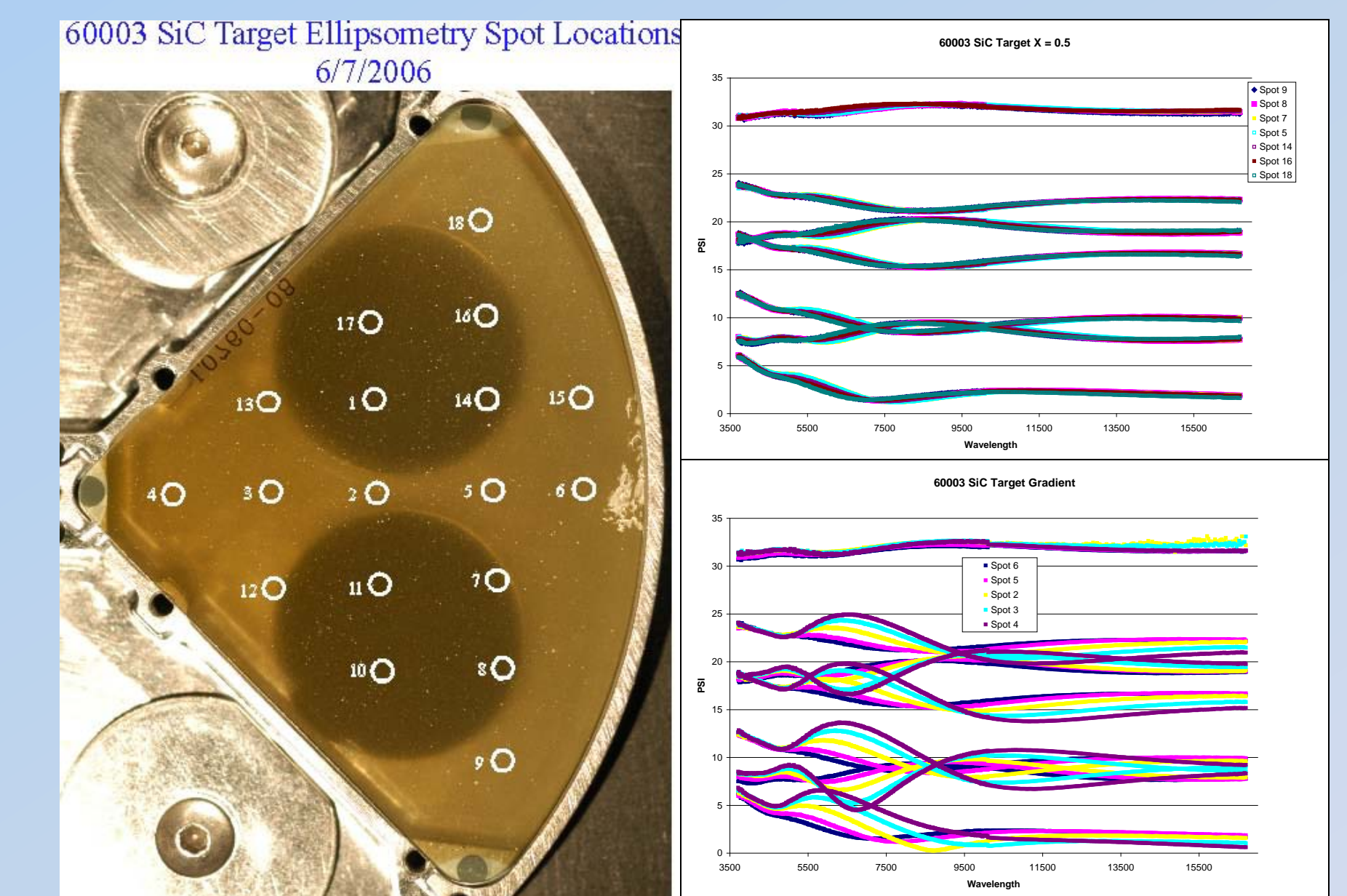
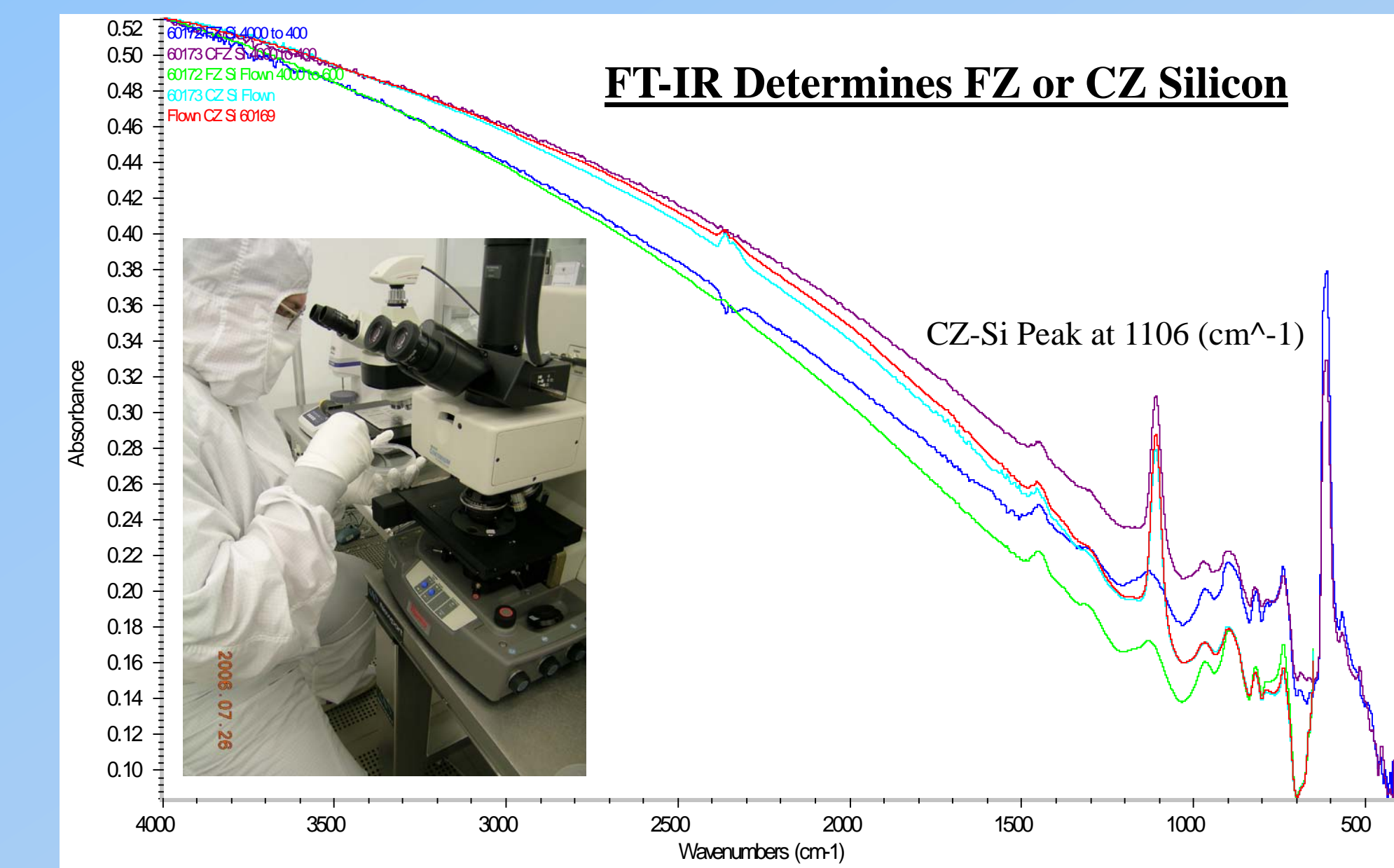
Spectroscopic Ellipsometry Measurements



Stereomicroscope



FT-IR Spectrometer



UPW/Megasonic Cleaning Macro Particle Decontamination

